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**Application Number** 

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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

First Named Inventor Davis et al Art Unit 2621 **Examiner Name** Not Known

Complete if Known

10/625,205

7/22/2003

2 of **Attorney Docket Number** C03-003

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Examiner Signature	/Kanjibhai Patel/	Date Considered	10/27/2006
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stitute for form 1449B/PTO

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Complete if Known Application Number 10/625,205 7/22/2003 Filing Date Davis First Named Inventor 2621 Art Unit Not Known Examiner Name

(Use as many sheets as necessary) 2 2 C03-003 Sheet Attorney Docket Number

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Signature	/Kanjibhai Patel/	Considered	11/01/2006
Signature	,,	Considered_	

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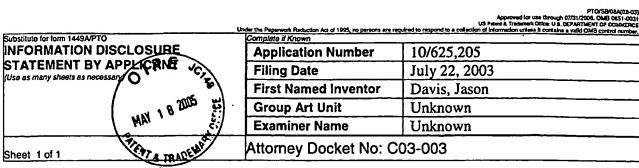
This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS

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STATEMENT BY APPLICANT (Use as many sheets as necessary)	Application Number	10/625,205
OIP E VOIR	Filing Date	July 22, 2003
111 1 2005 2	First Named Inventor	Davis, Jason
1 301	Group Art Unit	Unknown
JUL 1 & 2005 E	Examiner Name	Unknown
Sheet 1 of 1	Attorney Docket No: Co	03-003

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